

<b>Notice of References Cited</b>	Application/Control No. 10/614,242	Applicant(s)/Patent Under Reexamination OKUDA ET AL.	
	Examiner Viet Q Nguyen	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,313,674	11-2001	Akita et al.	327/155
*	B	US-6,400,643	06-2002	Setogawa, Jun	365/233
*	C	US-6,417,715	07-2002	Hamamoto et al.	327/291
*	D	US-6,594,197	07-2003	Okuda et al.	365/233
*	E	US-6,603,687	08-2003	Jun et al.	365/194
*	F	US-6,621,352	09-2003	Matsumoto et al.	331/1A
*	G	US-6,703,879	03-2004	Okuda et al.	327/158
*	H	US-6,754,133	06-2004	Morita et al.	365/233
*	I	US-2001/0052808	12-2001	Hamamoto et al.	327/291
*	J	US-2002/0008558	01-2002	Okuda et al.	327/175
*	K	US-2002/0180500	12-2002	Okuda et al.	327/158
*	L	US-2003/0123597	07-2003	Cho, Yong Deok	375/376
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP2001332086A	11-2001	Japan	Akita	G11C 11/407
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.